

INFORMATION DISCLOSURE STATEMENT  
BY APPLICANTOPIE  
SEP 11 2007SEARCHED  
INDEXED  
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Date: September 11, 2007

## U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR	2002-0051885 A1	05/2002	Braendle et al.			
BR						
CR						
DR						
ER						
FR						

## FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor/Applicant Name	English Abstract	Translation Readily Available		
					Enclosed	No	Enclosed	No
GR	09/095763	04/1997	JP	Mitsubishi Heavy Ind Ltd	X			
HR	10/140330	05/1998	JP	Hitachi Tool Eng Co Ltd	X			
IR	08-209335	08/1996	JP	Hitachi Tool Eng Ltd.	X			
JR	4-300104	10/1992	JP	Mitsubishi Material Corp	X			
KR	5-177413	07/1993	JP	Sumitomo Electric Industries	X			
LR	8-209334	08/1996	JP	Hitachi Tool	X			
MR								
NR								
OR								
PR								

## OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

QR	I.C. Noyan, J. B. Cohen; "5 Determination of Strain and Stress Fields by Diffraction Methods"; Residual Stress Management by Diffraction and Interpretation; Springer-Verlag; New York; 1987; pp. 117-130			
RR	International Search Report December 20, 2005 in International Application No. PCT/SE2005/001311			
SR				
TR				
UR				
VR				
WR				
XR				

Examiner /Archene Turner/ Date Considered: 5/09

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /A.T./